February 2007



SEMICONDUCTOR®

FDMS2734 N-Channel UltraFET Trench[®] MOSFET

250V, 14A, 122mΩ

Features

- Max $r_{DS(on)}$ = 122m Ω at V_{GS} = 10V, I_D = 2.8A
- Max $r_{DS(on)}$ = 130m Ω at V_{GS} = 6V, I_D = 1.7A
- Low Miller Charge
- Optimized efficiency at high frequencies
- RoHS Compliant

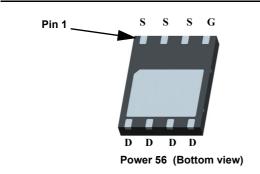


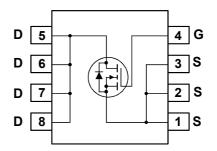
General Description

UltraFET devices combine characteristics that enable benchmark efficiency in power conversion applications. Optimized for $r_{DS(on)}$, low ESR, low total and Miller gate charge, these devices are ideal for high frequency DC to DC converters.

Application

DC - DC Conversion





MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V _{DS}	Drain to Source Voltage			250	V	
V _{GS}	Gate to Source Voltage			±20	V	
	Drain Current -Continuous (Silicon limited)	T _C = 25°C		14		
I _D	-Continuous	T _A = 25°C	(Note 1a)	2.8	A	
	-Pulsed			16		
P _D	Power Dissipation	T _C = 25°C		78	W	
	Power Dissipation	T _A = 25°C	(Note 1a)	2.5		
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C	

Thermal Characteristics

$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	1.6	°C/W
R_{\thetaJA}	Thermal Resistance, Junction to Ambient (Note 1a)	50	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS2734	FDMS2734	Power 56	13"	12mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics	·				
BV _{DSS}	Drain to Source Breakdown Voltage	I _D = 250μA, V _{GS} = 0V	250			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25°C		250		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 200V,			1	μA
I _{GSS}	Gate to Source Leakage Current	V_{GS} = ±20V, V_{GS} = 0V			±100	nA
On Chara	acteristics (Note 2)					
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2	3	4	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to $25^{\circ}C$		-11		mV/°C
	Drain to Source On Resistance	V _{GS} = 10V, I _D = 2.8A		105	122	
r _{DS(on)}		V _{GS} = 6V, I _D = 1.7A		110	130	mΩ
		V_{GS} = 10V, I_D = 2.8A T_J = 125°C		217	258	
g _{FS}	Forward Transconductance	V _{DS} = 10V, I _D = 2.8A		11		S
•	Characteristics			I	Γ	I
C _{iss}	Input Capacitance			1775	2365	pF
C _{oss}	Output Capacitance	= f = 1MHz		80	110	pF
C _{rss}	Reverse Transfer Capacitance			25	40	pF
R _g	Gate Resistance	f = 1MHz		0.9		Ω
Switching	g Characteristics					
t _{d(on)}	Turn-On Delay Time			22	36	ns
t _r	Rise Time	$V_{DD} = 125V, I_D = 2.8A$		10	20	ns
t _{d(off)}	Turn-Off Delay Time	– V _{GS} = 10V, R _{GEN} = 6Ω		36	58	ns
t _f	Fall Time			12	22	ns
Q _{g(TOT)}	Total Gate Charge at 10V	$V_{GS} = 0V$ to 10V $V_{DD} = 125V$		30	42	nC
Q _{gs}	Gate to Source Gate Charge	I _D = 2.8A		7		nC
Q _{gd}	Gate to Drain "Miller" Charge			9		nC
Drain-So	urce Diode Characteristics					
Drain-So V _{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0V, I _S = 2.8A (Note 2)		0.75	1.20	V
	1	V _{GS} = 0V, I _S = 2.8A (Note 2) 		0.75 79	1.20 119	V ns

Notes: 1: R_{0JA} is determined with the device mounted on a 1in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



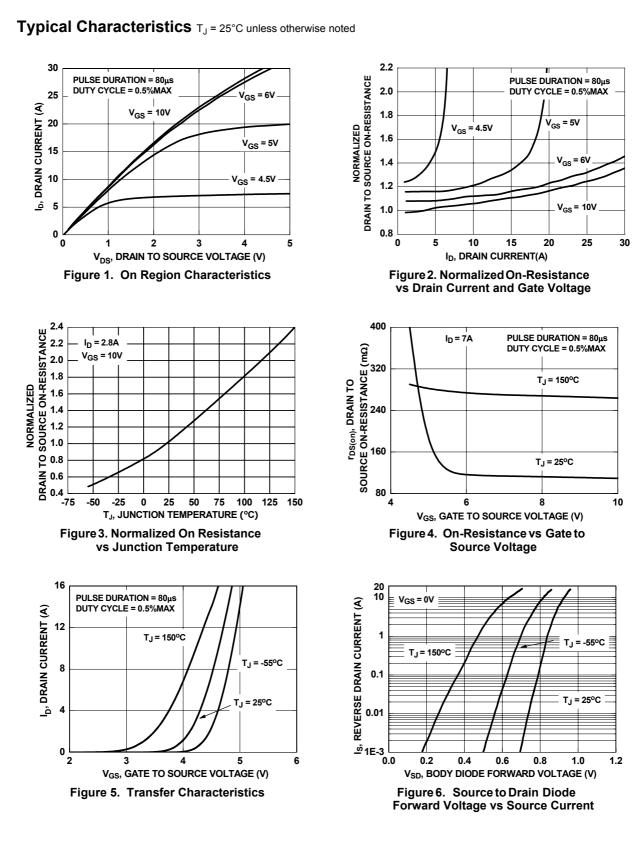
a. 50° C/W when mounted on a 1 in² pad of 2 oz copper

b. 125°C/W when mounted on a minimum pad of 2 oz copper

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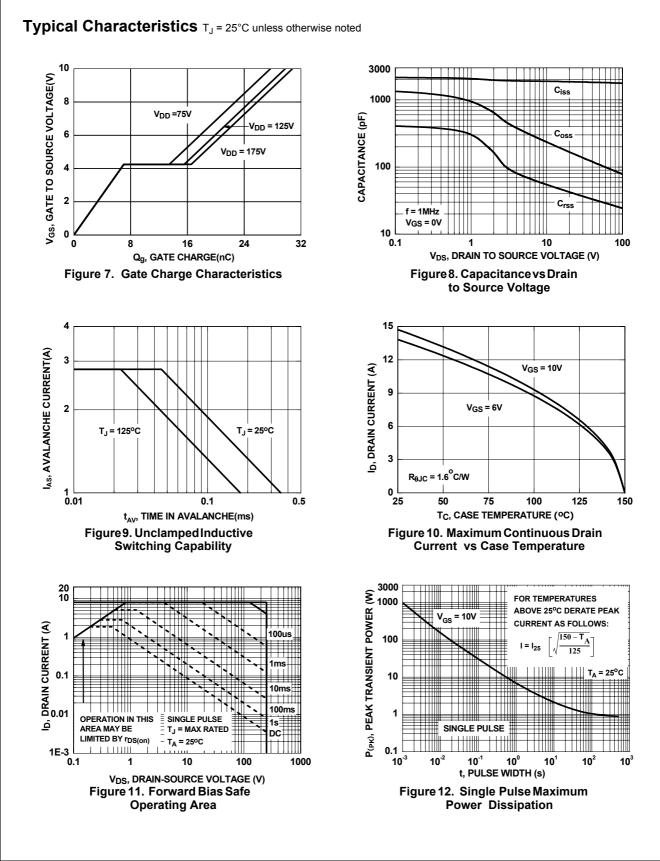
2: Pulse Test: Pulse Width < 300µs, Duty cycle < 2.0%.

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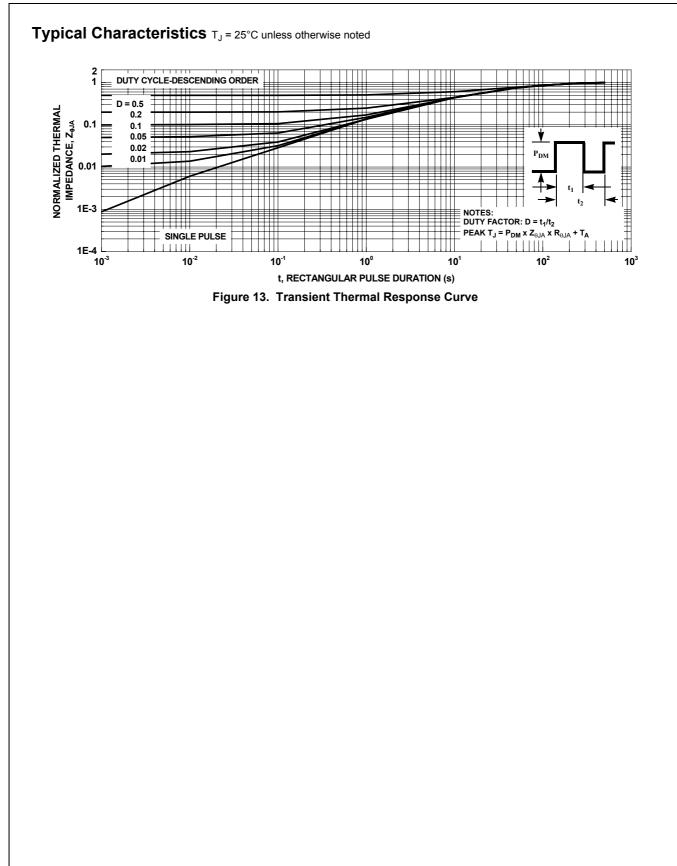
FDMS2734 Rev.C

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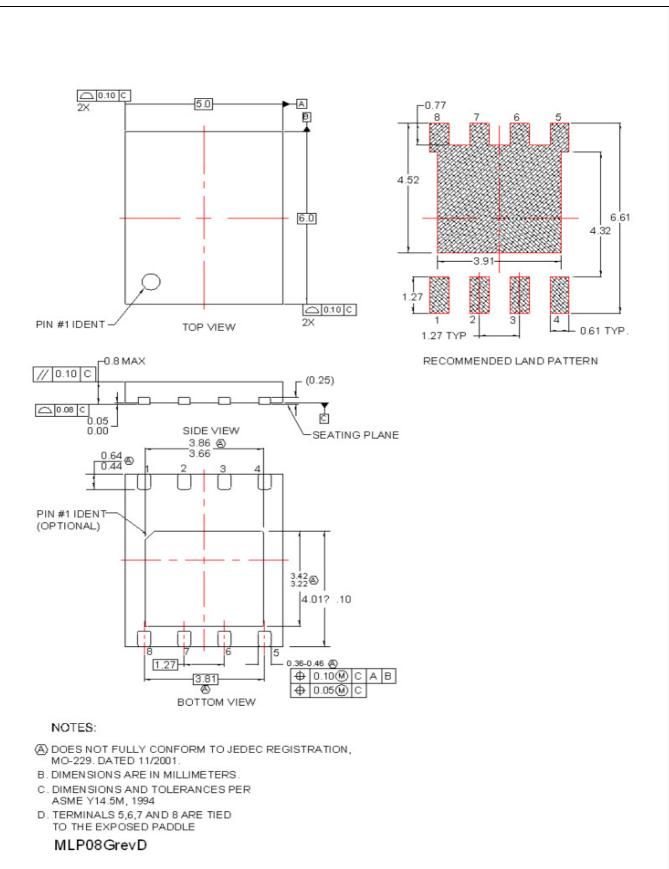


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